

Search Notes

Application/Control No.

10/786,093

Examiner

Seung H. Lee

Applicant(s)/Patent under
Reexamination

TOYAMA ET AL.

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
235	462.41	8/18/2005	SHL
235	462.42	8/18/2005	SHL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
235/454 (see printouts)	8/18/2005	SHL
235/472.01 (see printouts)	8/18/2005	SHL
359/599,707 (see printouts)	8/18/2005	SHL
A. Kim (235)	8/18/2005	SHL
J. Fureman (235)	8/18/2005	SHL
R. Mack (359)	8/18/2005	SHL